AMENDMENTS TO THE CLAIMS:

Complete Listing of Claims

Claim 1. (currently amended) A method of measuring jitter in a device under test comprising the steps of:

provided a coherent sample signal to the device under test;

unwrapping the data from the device;

performing FFT of the unwrapped data;

removing the DC harmonic and the fundamental <u>frequency</u> from the FFT of the unwrapped data;

performing an inverse FFT of the FFT of the unwrapped data with the DC harmonic and fundamental removed to get <u>a</u> code error;

adjusting the code error to a predetermined phase;

determining the variance of the code error at <u>a</u> ~~the~~ low slew rate;

determining the variance of the code error at <u>a</u> ~~the~~ high slew rate; <u>and</u>

calculating the jitter on each angle from the <u>variance of the code error</u> <u>determined at the</u> high slew <u>rate</u> ~~variance by each angle~~ and the <u>variance of the</u> <u>code error determined at the</u> low slew rate ~~variance~~.

Claim 2. (currently amended) The method of claim 1 wherein said method includes the step of removing sparkle codes before adjusting the ~~phase~~ code error.

Claim 3. (original) The method of claim 2 including the step of averaging the jitter for all angles that the jitter is calculated.

Claim 4. (original) The method of claim 1 including the step of averaging the jitter for all angles that the jitter is calculated.